

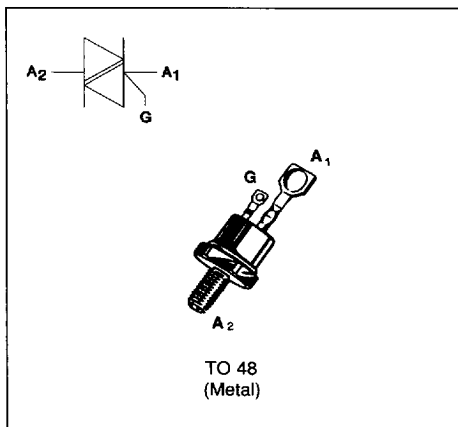
STANDARD TRIACS

FEATURES

- I_{GT} SPECIFIED IN FOUR QUADRANTS
- EXCELLENT THERMAL IMPEDANCE PACKAGE
- HIGH COMMUTATION, $(dV/dt)_c > 10 \text{ V}/\mu\text{s}$

DESCRIPTION

The TRAL 1135D ---> 3835D use high performance passivated glass triac technology. These high power triacs on TO 48 package are well adapted for use on 220 V and 380 V main, suitable for applications such : motor control, heating control, light dimmer...



ABSOLUTE RATINGS (limiting values)

Symbol	Parameter		Value	Unit
$I_T(\text{RMS})$	RMS on-state current (360° conduction angle)	$T_c = 80^\circ \text{C}$	35	A
I_{TSM}	Non repetitive surge peak on-state current (T_j initial = 25°C)	$t_p = 8.3 \text{ ms}$	330	A
		$t_p = 10 \text{ ms}$	300	
I_{2t}	I_{2t} value	$t_p = 10 \text{ ms}$	450	A^2s
di/dt	Critical rate of rise of on-state current Gate supply : $I_G = 1 \text{ A}$ $di_G/dt = 1 \text{ A}/\mu\text{s}$	Repetitive $F = 50 \text{ Hz}$	20	$\text{A}/\mu\text{s}$
		Non Repetitive	100	
T_{stg} T_j	Storage and operating junction temperature range		- 40 to + 150 - 40 to + 125	$^\circ \text{C}$ $^\circ \text{C}$
T_l	Maximum lead temperature for soldering during 10 s at 4.5 mm from case		230	$^\circ \text{C}$

Symbol	Parameter	TRAL				Unit
		1135D	2235D	3335D	3835D	
V_{DRM} V_{RRM}	Repetitive peak off-state voltage $T_j = 125^\circ \text{C}$	200	400	600	700	V

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R _{th} (c-h)	Contact (case-heatsink) for recommended stud torque	0.4	°C/W
R _{th} (j-c) DC	Junction to case for DC	1.1	°C/W
R _{th} (j-c) AC	Junction to case for 360° conduction angle (F = 50 Hz)	0.8	°C/W

GATE CHARACTERISTICS (maximum values)

P_G (AV) = 1W P_{GM} = 40W (tp = 20 μs) I_{GM} = 6A (tp = 20 μs) V_{GM} = 16V (tp = 20 μs).

ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions		Quadrant		Value	Unit
I _{GT}	V _D =12V (DC) R _L =33Ω	T _j =25°C	I-II-III	MAX	100	mA
			IV	MAX	150	
V _{GT}	V _D =12V (DC) R _L =33Ω	T _j =25°C	I-II-III-IV	MAX	1.5	V
V _{GD}	V _D =V _{DRM} R _L =3.3kΩ	T _j =110°C	I-II-III-IV	MIN	0.2	V
t _{gt}	V _D =V _{DRM} I _G = 500mA dI _G /dt = 3A/μs	T _j =25°C	I-II-III-IV	TYP	3	μs
I _L	I _G =1.2 I _{GT}	T _j =25°C	I-III-IV	TYP	100	mA
			II		200	
I _H *	I _T = 500mA gate open	T _j =25°C		MAX	100	mA
V _{TM} *	I _{TM} = 53A tp= 380μs	T _j =25°C		MAX	2	V
I _{DRM} I _{RRM}	V _{DRM} Rated V _{RRM} Rated	T _j =25°C		MAX	0.02	mA
		T _j =110°C		MAX	4	
dV/dt *	Linear slope up to V _D =67%V _{DRM} gate open	T _j =110°C		MIN	250	V/μs
(dV/dt) _c *	(dI/dt) _c = 15.5A/ms	T _j =110°C		MIN	10	V/μs

* For either polarity of electrode A₂ voltage with reference to electrode A₁.

Fig.1 : Maximum RMS power dissipation versus RMS on-state current ($F=50\text{Hz}$).
(curves are cut off by $(di/dt)_c$ limitation)

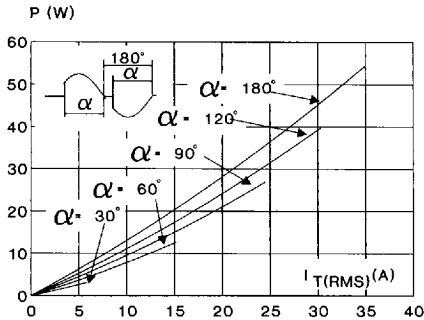


Fig.3 : RMS on-state current versus case temperature.

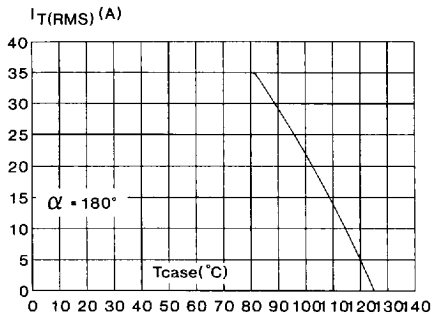


Fig.5 : Relative variation of gate trigger current and holding current versus junction temperature.

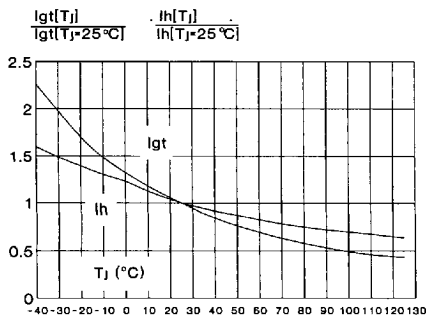


Fig.2 : Correlation between maximum RMS power dissipation and maximum allowable temperatures (T_{amb} and T_{case}) for different thermal resistances heatsink + contact.

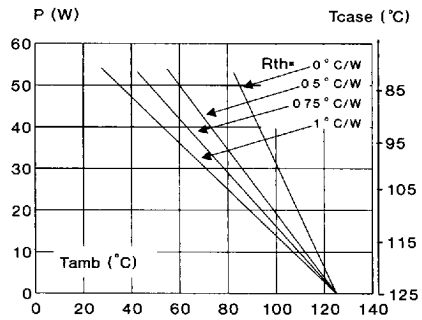


Fig.4 : Thermal transient impedance junction to case and junction to ambient versus pulse duration.

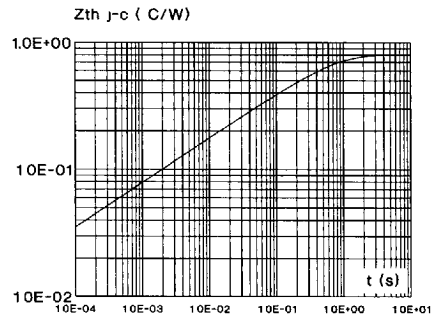


Fig.6 : Non Repetitive surge peak on-state current versus number of cycles.

